## **Power MOSFET** 40 V, 0.82 mΩ, 330 A, Single N–Channel

#### Features

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses

**MAXIMUM RATINGS** (T<sub>J</sub> =  $25^{\circ}$ C unless otherwise noted)

- NTMFS5C410NLTWF Wettable Flank Option for Enhanced Optical Inspection
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant



## **ON Semiconductor®**

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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	$0.82~\text{m}\Omega$ @ 10 V	220.4
40 V	1.2 mΩ @ 4.5 V	330 A

D (5,6)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	40	V
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain		$T_C = 25^{\circ}C$	۱ <sub>D</sub>	330	А
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	$T_{C} = 100^{\circ}C$		230	
Power Dissipation	State	T <sub>C</sub> = 25°C	PD	167	W
R <sub>θJC</sub> (Note 1)		$T_{C} = 100^{\circ}C$		83	
Continuous Drain		$T_A = 25^{\circ}C$	Ι <sub>D</sub>	50	А
Current R <sub>θJA</sub> (Notes 1, 2, 3)	Steady	$T_A = 100^{\circ}C$		35	
Power Dissipation $R_{\theta JA}$ (Notes 1 & 2)	State	$T_A = 25^{\circ}C$	PD	3.8	W
		$T_A = 100^{\circ}C$		1.9	
Pulsed Drain Current	$T_{A} = 25^{\circ}$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	900	А
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	–55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	169	А
Single Pulse Drain–to–Source Avalanche Energy ( $I_{L(pk)} = 29 \text{ A}$ )			E <sub>AS</sub>	706	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			ΤL	260	°C
Stresses exceeding those	listed in t	he Maximum R	atings table	may dam	age the

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

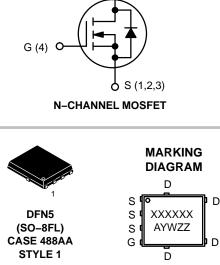
#### THERMAL RESISTANCE MAXIMUM RATINGS

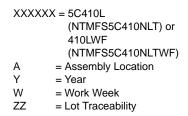
Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{ extsf{ heta}JC}$	0.9	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\thetaJA}$	39	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.

3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.





#### ORDERING INFORMATION

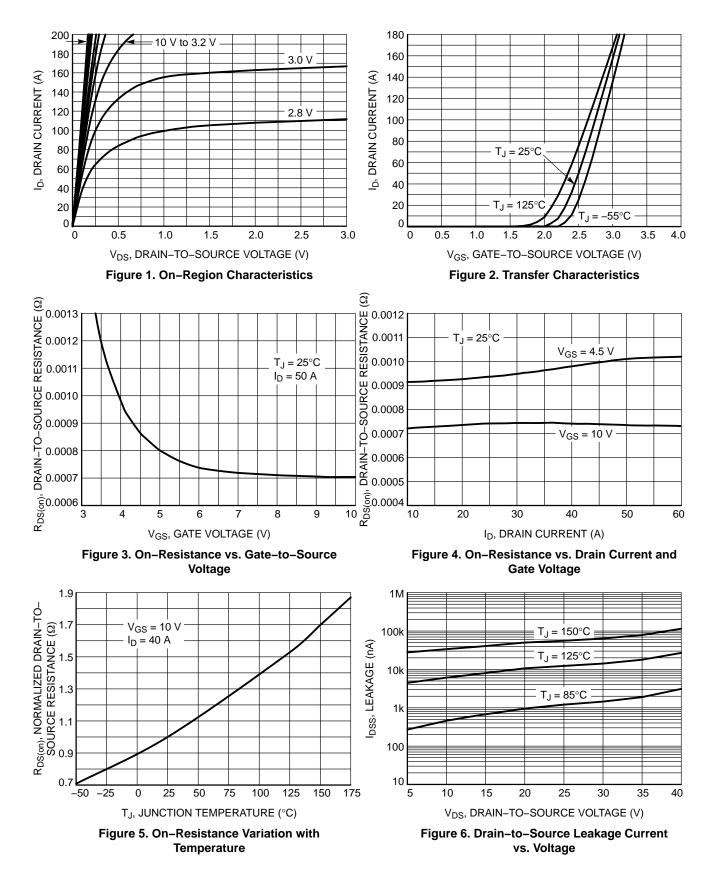
See detailed ordering, marking and shipping information on page 5 of this data sheet.

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

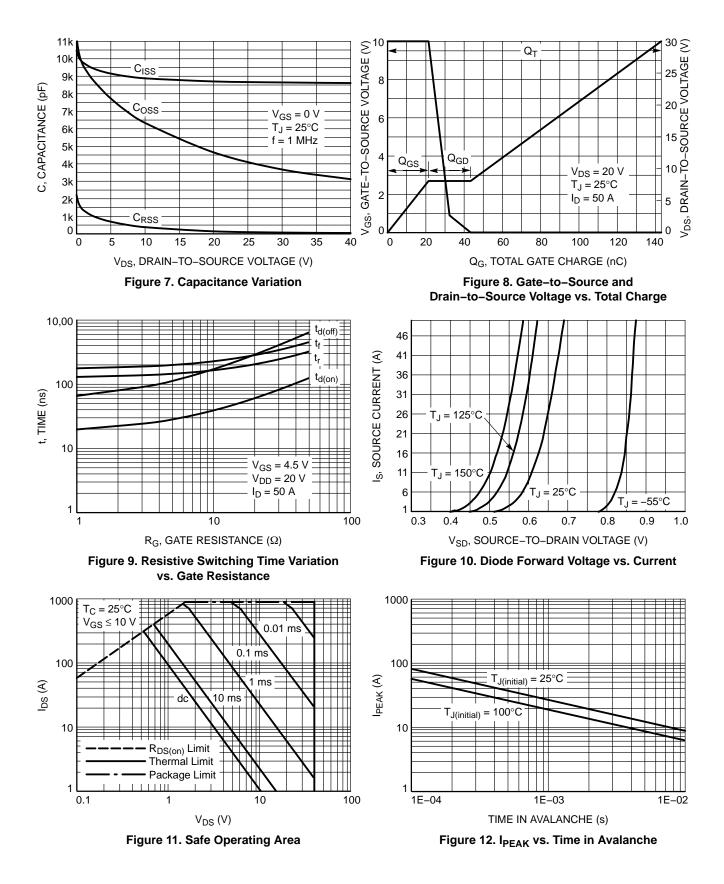
Parameter	Symbol	Test Cond	ition	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \ \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				21.2		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V,$	T <sub>J</sub> = 25 °C			10	
		$V_{DS} = 40 V$ $T_{J} = 125^{\circ}C$				250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 250 \ \mu A$		1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.75		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		0.65	0.82	_
		$V_{GS} = 4.5 V$	I <sub>D</sub> = 50 A		0.95	1.2	mΩ
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 50 A			190		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE					-	
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			8862		
Output Capacitance	C <sub>OSS</sub>				4156		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				116		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 20 V; $I_{D}$ = 50 A			66		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 20 V; $I_{D}$ = 50 A			143		
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 20 V; I <sub>D</sub> = 50 A			6.75		nC
Gate-to-Source Charge	Q <sub>GS</sub>				21.4		
Gate-to-Drain Charge	Q <sub>GD</sub>				22		
Plateau Voltage	V <sub>GP</sub>				2.7		V
SWITCHING CHARACTERISTICS (Note &	5)					-	
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 20 V, $I_{D}$ = 50 A, $R_{G}$ = 1.0 $\Omega$			20		ns
Rise Time	tr				130		
Turn–Off Delay Time	t <sub>d(OFF)</sub>				66		
Fall Time	t <sub>f</sub>				177		
DRAIN-SOURCE DIODE CHARACTERIS	TICS				-		
Forward Diode Voltage	V <sub>SD</sub>	$V_{GS} = 0 V,$ $I_{S} = 50 A$	$T_J = 25^{\circ}C$		0.73	1.2	
			T <sub>J</sub> = 125°C		0.6		V
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/µs, I <sub>S</sub> = 50 A			79.5		ns
Charge Time	t <sub>a</sub>				39		
Discharge Time	t <sub>b</sub>				40.5		
Reverse Recovery Charge	Q <sub>RR</sub>				126		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width  $\leq 300 \ \mu$ s, duty cycle  $\leq 2\%$ . 5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**



#### **TYPICAL CHARACTERISTICS**



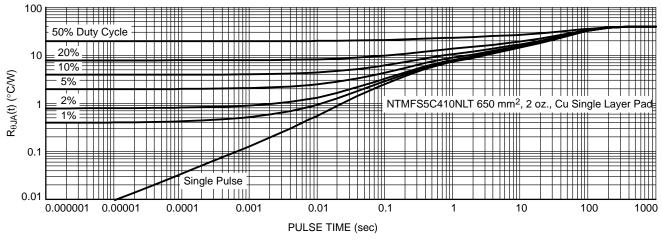


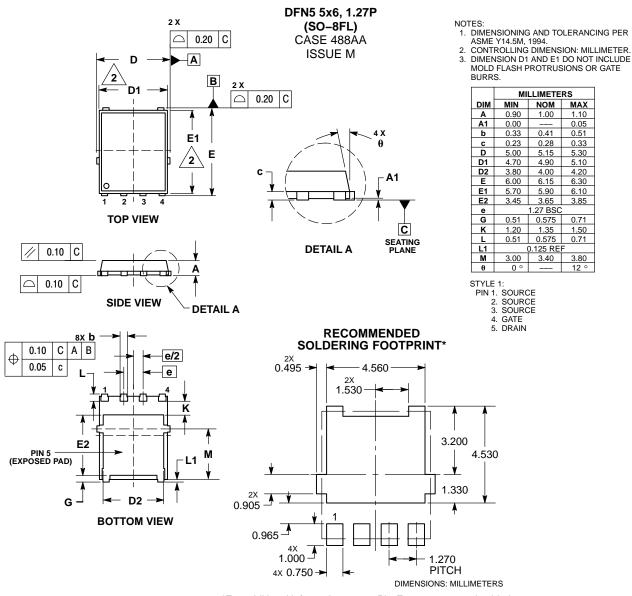
Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTMFS5C410NLTT1G	5C410L	DFN5 (Pb–Free)	1500 / Tape & Reel
NTMFS5C410NLTWFT1G	410LWF	DFN5 (Pb–Free, Wettable Flanks)	1500 / Tape & Reel
NTMFS5C410NLTT3G	5C410L	DFN5 (Pb–Free)	5000 / Tape & Reel
NTMFS5C410NLTWFT3G	410LWF	DFN5 (Pb–Free, Wettable Flanks)	5000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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#### PUBLICATION ORDERING INFORMATION

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